

CONSOLIDATED VERSION

VERSION CONSOLIDÉE



**High-voltage switchgear and controlgear –
Part 101: Synthetic testing**

**Appareillage à haute tension –
Partie 101: Essais synthétiques**



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**High-voltage switchgear and controlgear –
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HIGH-VOLTAGE SWITCHGEAR AND CONTROLGEAR –

Part 101: Synthetic testing

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This Consolidated version of IEC 62271-101 bears the edition number 2.1. It consists of the second edition (2012-10) [documents 17A/1015/FDIS and 17A/1024/RVD] and its amendment 1 (2017-11) [documents 17A/1149/FDIS and 17A/1154/RVD]. The technical content is identical to the base edition and its amendment.

In this Redline version, a vertical line in the margin shows where the technical content is modified by amendment 1. Additions are in green text, deletions are in strikethrough red text. A separate Final version with all changes accepted is available in this publication.

International Standard IEC 62271-101 has been prepared by subcommittee 17A: High-voltage switchgear and controlgear, of IEC technical committee 17: Switchgear and controlgear.

This second edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the first edition:

- addition of the new rated voltages of 1 100 kV and 1 200 kV;
- revision of Annex F regarding circuit-breakers with opening resistors;
- alignment with the second edition of IEC 62271-100:2008 and its Amendment 1 (2012).

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This publication shall be read in conjunction with IEC 62271-100, published in 2008, to which it refers. The numbering of the subclauses of Clause 6 is the same as in IEC 62271-100. However, not all subclauses of IEC 62271-100 are addressed; merely those where synthetic testing has introduced changes.

A list of all the parts in the IEC 62271 series, under the general title *High-voltage switchgear and controlgear*, can be found on the IEC website.

The committee has decided that the contents of the base publication and its amendment will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

INTRODUCTION to the Amendment

This amendment includes the following significant technical changes:

- the test procedure for test-duty T100a has been aligned with IEC 62271-100;
- Annexes A through D have been transferred to IEC 62271-306;
- Annex I has been revised and now includes Annex P of IEC 62271-100;
- Annexes K, L and N have been revised.

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HIGH-VOLTAGE SWITCHGEAR AND CONTROLGEAR –

Part 101: Synthetic testing

1 Scope

This part of IEC 62271 mainly applies to a.c. circuit-breakers within the scope of IEC 62271-100. It provides the general rules for testing a.c. circuit-breakers, for making and breaking capacities over the range of test duties described in 6.102 to 6.111 of IEC 62271-100:2008, by synthetic methods.

It has been proven that synthetic testing is an economical and technically correct way to test high-voltage a.c. circuit-breakers according to the requirements of IEC 62271-100 and that it is equivalent to direct testing.

The methods and techniques described are those in general use. The purpose of this standard is to establish criteria for synthetic testing and for the proper evaluation of results. Such criteria will establish the validity of the test method without imposing restraints on innovation of test circuitry.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 62271-100:2008, *High-voltage switchgear and controlgear – Part 100: Alternating current circuit-breakers*

IEC 62271-100:2008/AMD1:2012

IEC 62271-100:2008/AMD2:2017

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 62271-100, as well as the following, apply.

3.1

direct test

test in which the applied voltage, the current and the transient and power-frequency recovery voltages are all obtained from a circuit having a single-power source, which may be a power system or special alternators as used in short-circuit testing stations or a combination of both

3.2

synthetic test

test in which all of the current, or a major portion of it, is obtained from one source (current circuit), and in which the applied voltage and/or the recovery voltages (transient and power frequency) are obtained wholly or in part from one or more separate sources (voltage circuits)

3.3

test circuit-breaker

circuit-breaker under test